

SPP17N80C3 SPA17N80C3

Cool MOS™ Power Transistor

Feature

- New revolutionary high voltage technology
- Worldwide best R_{DS(on)} in TO 220
- Ultra low gate charge
- Periodic avalanche rated
- Extreme dv/dt rated
- Ultra low effective capacitances
- Improved transconductance
- PG-TO-220-3-31: Fully isolated package (2500 VAC; 1 minute)

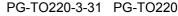
PG-TO220-3-31 SP000216353

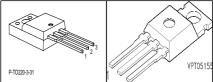
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC⁰⁾ for target applications

Package

PG-TO220

V _{DS}	800	V
R _{DS(on)}	0.29	Ω
I _D	17	Α

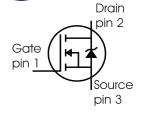












Maximum Ratings

SPP17N80C3

SPA17N80C3

Type

Parameter	Symbol	Va	Unit	
		SPP	SPA	
Continuous drain current	I _D			Α
T _C = 25 °C		17	17 ¹⁾	
<i>T</i> _C = 100 °C		11	11 ¹⁾	
Pulsed drain current, t_p limited by T_{jmax}	I _{D puls}	51	51	Α
Avalanche energy, single pulse	E _{AS}	670	670	mJ
$I_{\rm D}$ =3.4A, $V_{\rm DD}$ =50V				
Avalanche energy, repetitive t_{AR} limited by T_{jmax}^{2}	E _{AR}	0.5	0.5	
I _D =17A, V _{DD} =50V				
Avalanche current, repetitive t_{AR} limited by T_{jmax}	I _{AR}	17	17	Α
Gate source voltage	V_{GS}	±20	±20	V
Gate source voltage AC (f >1Hz)	V_{GS}	±30	±30	
Power dissipation, $T_C = 25^{\circ}C$	P _{tot}	208	42	W
Operating and storage temperature	T _j , T _{stg}	-55	+150	°C

Ordering Code

Q67040-S4353

Marking

17N80C3

17N80C3



Maximum Ratings

Parameter	Symbol	Value	Unit
Drain Source voltage slope	dv/dt	50	V/ns
$V_{\rm DS}$ = 640 V, $I_{\rm D}$ = 17 A, $T_{\rm j}$ = 125 °C			

Thermal Characteristics

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Thermal resistance, junction - case	R_{thJC}	-	-	0.6	K/W
Thermal resistance, junction - case, FullPAK	R _{thJC FP}	-	-	3.6	
Thermal resistance, junction - ambient, leaded	$R_{\rm thJA}$	-	-	62	
Thermal resistance, junction - ambient, FullPAK	R _{thJA FP}	-	-	80	
SMD version, device on PCB:	R_{thJA}				
@ min. footprint		-	_	62	
@ 6 cm ² cooling area ³⁾		-	35	-	
Soldering temperature, wavesoldering	T_{sold}	-	-	260	°C
1.6 mm (0.063 in.) from case for 10s ⁴⁾					

Electrical Characteristics, at T_i =25°C unless otherwise specified

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0V, I _D =0.25mA	800	ı	-	V
Drain-Source avalanche	V _{(BR)DS}	V _{GS} =0V, I _D =17A	-	870	-	
breakdown voltage	, ,					
Gate threshold voltage	V _{GS(th)}	/ _D =1000μA, / _{GS} =V _D	2.1	3	3.9	
Zero gate voltage drain current	I _{DSS}	V _{DS} =800V, V _{GS} =0V,				μΑ
		<i>T</i> _j =25°C	-	0.5	25	
		<i>T</i> _j =150°C	-	-	250	
Gate-source leakage current	I_{GSS}	V _{GS} =20V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10V, I _D =11A				Ω
		<i>T</i> _j =25°C	-	0.25	0.29	
		<i>T</i> _j =150°C	-	0.78	-	
Gate input resistance	R _G	f=1MHz, open drain	-	0.7	-	



Electrical Characteristics

Parameter	Symbol	Conditions	Conditions Values			Unit
			min.	typ.	max.	
Transconductance	g _{fs}	$V_{\rm DS} \ge 2*I_{\rm D}*R_{\rm DS(on)max}$ $I_{\rm D}=11A$	-	15	-	S
Input capacitance	C _{iss}	$V_{\rm GS}$ =0V, $V_{\rm DS}$ =25V,	-	2320	-	pF
Output capacitance	Coss	f=1MHz	-	1250	-	
Reverse transfer capacitance	C _{rss}		-	60	-	
Effective output capacitance,5)	C _{o(er)}	V _{GS} =0V,	-	59	-	
energy related		V _{DS} =0V to 480V				
Effective output capacitance,6)	C _{o(tr)}		-	124	-	
time related						
Turn-on delay time	t _{d(on)}	V _{DD} =400V, V _{GS} =0/10V,	-	25	-	ns
Rise time	t _r	I _D =17A,	-	15	-	
Turn-off delay time	t _{d(off)}	R_{G} =4.7 Ω , T_{j} =125°C		72	82	
Fall time	t _f		-	6	9	

Gate Charge Characteristics

Gate to source charge	Q _{gs}	V _{DD} =640V, I _D =17A	-	12	-	nC
Gate to drain charge	Q _{gd}		-	46	-	
Gate charge total	Qg	V _{DD} =640V, I _D =17A,	-	91	177	
		V _{GS} =0 to 10V				
Gate plateau voltage	V _(plateau)	V _{DD} =640V, I _D =17A	-	6	-	V

⁰J-STD20 and JESD22

¹Limited only by maximum temperature

²Repetitve avalanche causes additional power losses that can be calculated as $P_{AV} = E_{AR} * f$.

 $^{^3}$ Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical without blown air.

⁴Soldering temperature for TO-263: 220°C, reflow

 $^{^5}C_{\rm o(er)}$ is a fixed capacitance that gives the same stored energy as $C_{\rm oss}$ while $V_{\rm DS}$ is rising from 0 to 80% $V_{\rm DSS}$.

 $^{^6}C_{
m o(tr)}$ is a fixed capacitance that gives the same charging time as $C_{
m oss}$ while $V_{
m DS}$ is rising from 0 to 80% $V_{
m DSS}$.

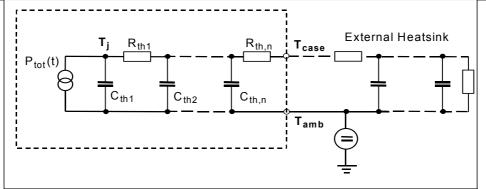


Electrical Characteristics

Parameter	Symbol	Conditions	ons Values			Unit
			min.	typ.	max.	
Inverse diode continuous	IS	T _C =25°C	-	-	17	Α
forward current						
Inverse diode direct current,	I _{SM}		-	-	51	1
pulsed						
Inverse diode forward voltage	V_{SD}	V _{GS} =0V, I _F =I _S	-	1	1.2	V
Reverse recovery time	t _{rr}	V _R =400V, I _F =I _S ,	-	550	-	ns
Reverse recovery charge	Q _{rr}	d <i>i</i> _F /d <i>t</i> =100A/μs	-	15	-	μC
Peak reverse recovery current	/ _{rrm}		-	51	-	Α
Peak rate of fall of reverse	di _{rr} /dt	<i>T</i> _j =25°C	-	1200	-	A/µs
recovery current						

Typical Transient Thermal Characteristics

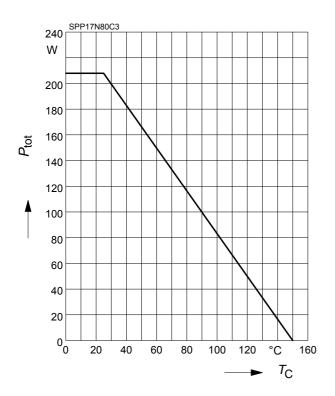
Symbol	Va	lue	Unit	Symbol	Va	lue	Unit
	SPP	SPA			SPP	SPA	
R _{th1}	0.00812	0.00812	K/W	C _{th1}	0.0003562	0.0003562	Ws/K
R _{th2}	0.016	0.016		C _{th2}	0.001337	0.001337	
R_{th3}	0.031	0.031		C _{th3}	0.001831	0.001831	
R_{th4}	0.114	0.16		C _{th4}	0.005033	0.005033	
R_{th5}	0.135	0.324		C _{th5}	0.012	0.008657	
R_{th6}	0.059	2.522		C _{th6}	0.092	0.412	





1 Power dissipation

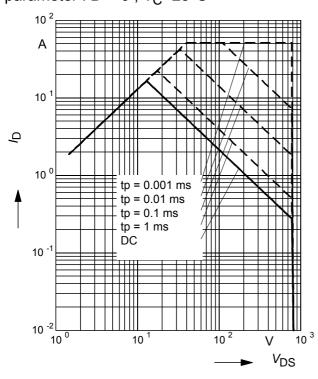
$$P_{\text{tot}} = f(T_{\text{C}})$$



3 Safe operating area

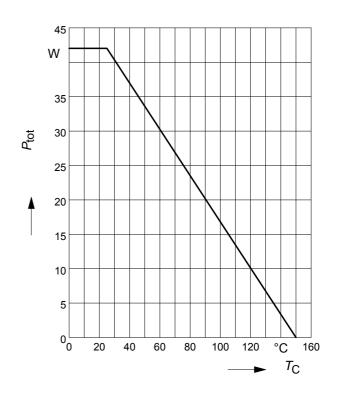
$$I_{D} = f(V_{DS})$$

parameter : D = 0 , $T_C = 25^{\circ}C$



2 Power dissipation FullPAK

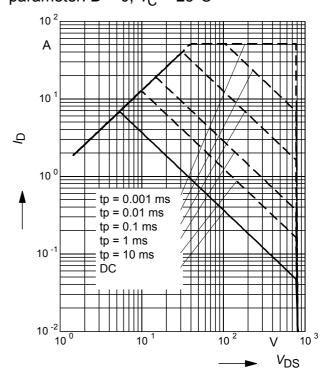
$$P_{\text{tot}} = f(T_{\text{C}})$$



4 Safe operating area FullPAK

$$I_{D} = f(V_{DS})$$

parameter: D = 0, $T_C = 25$ °C

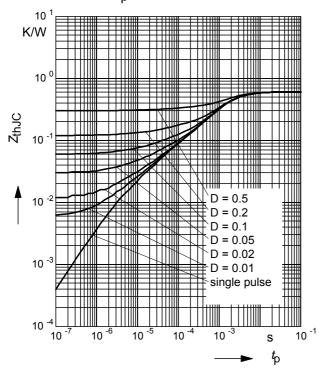




5 Transient thermal impedance

$$Z_{\text{thJC}} = f(t_{\text{p}})$$

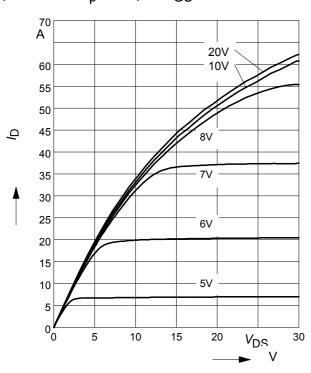
parameter: $D = t_p/T$



7 Typ. output characteristic

 $I_D = f(V_{DS}); T_j=25$ °C

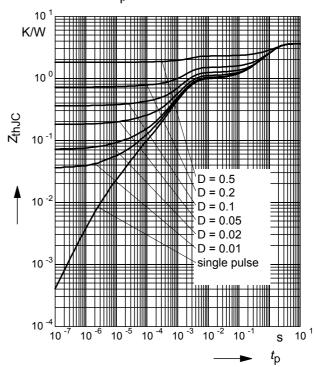
parameter: $t_p = 10 \mu s$, V_{GS}



6 Transient thermal impedance FullPAK

$$Z_{\mathsf{thJC}} = f\left(t_{\mathsf{p}}\right)$$

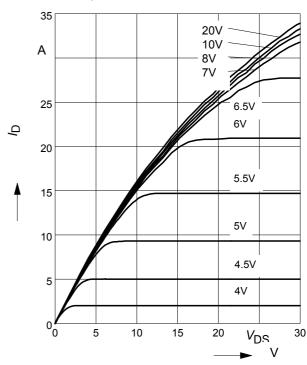
parameter: $D = t_D/t$



8 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{j}=150^{\circ}C$

parameter: t_p = 10 μ s, V_{GS}

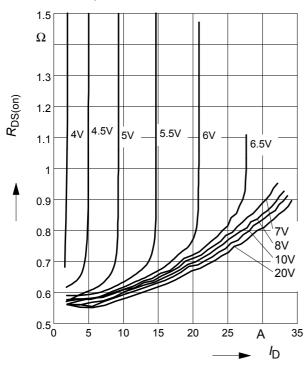




9 Typ. drain-source on resistance

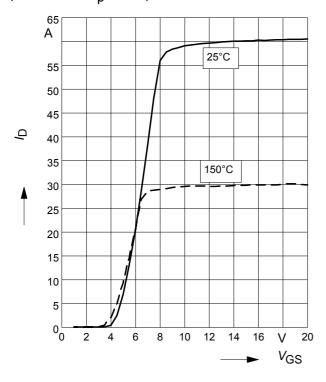
 $R_{\mathrm{DS(on)}} = f(I_{\mathrm{D}})$

parameter: T_j =150°C, V_{GS}



11 Typ. transfer characteristics

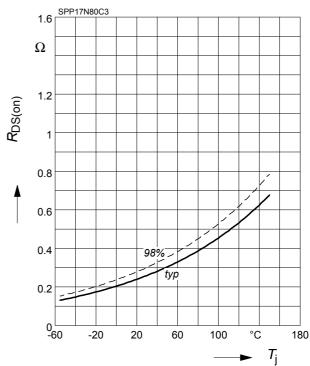
 $I_{\rm D}$ = $f(V_{\rm GS})$; $V_{\rm DS}$ $\geq 2 \times I_{\rm D} \times R_{\rm DS(on)max}$ parameter: $t_{\rm D}$ = 10 μ s



10 Drain-source on-state resistance

 $R_{\mathsf{DS}(\mathsf{on})} = f(T_{\mathsf{j}})$

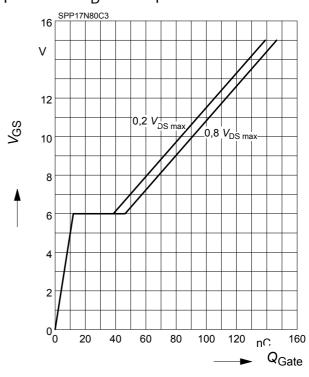
parameter : I_D = 11 A, V_{GS} = 10 V



12 Typ. gate charge

 $V_{GS} = f (Q_{Gate})$

parameter: I_D = 17 A pulsed

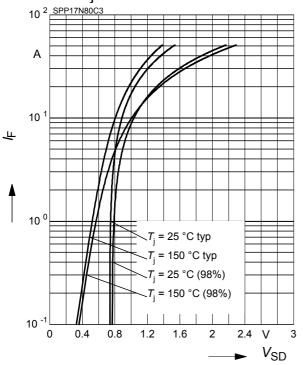




13 Forward characteristics of body diode

$$I_{\mathsf{F}} = f(\mathsf{V}_{\mathsf{SD}})$$

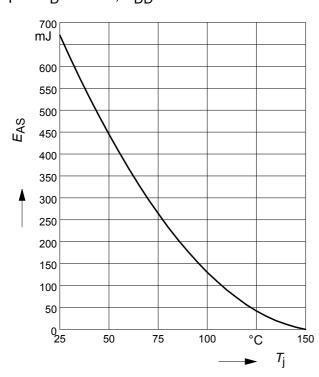
parameter: T_i , $t_p = 10 \mu s$



15 Avalanche energy

$$E_{AS} = f(T_i)$$

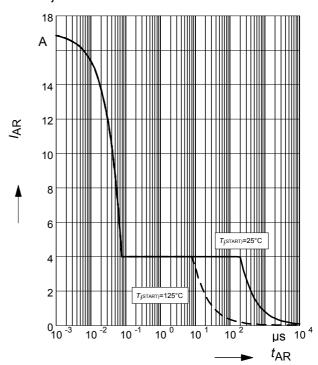
par.: $I_D = 3.4 \text{ A}, V_{DD} = 50 \text{ V}$



14 Avalanche SOA

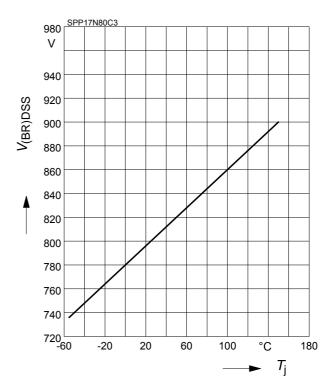
$$I_{AR} = f(t_{AR})$$

par.: $T_j \le 150 \, ^{\circ}\text{C}$



16 Drain-source breakdown voltage

$$V_{(BR)DSS} = f(T_j)$$

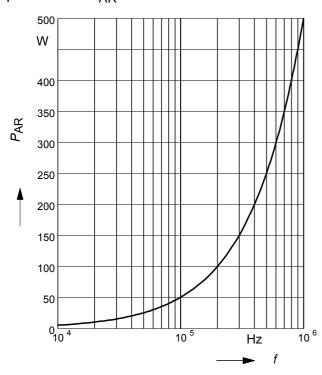




17 Avalanche power losses

$P_{AR} = f(f)$

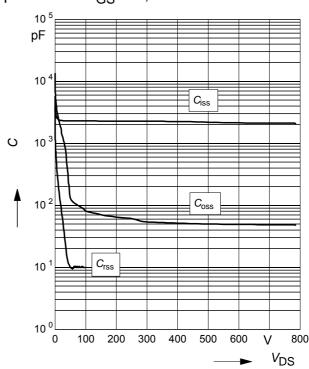
parameter: EAR=0.5mJ



18 Typ. capacitances

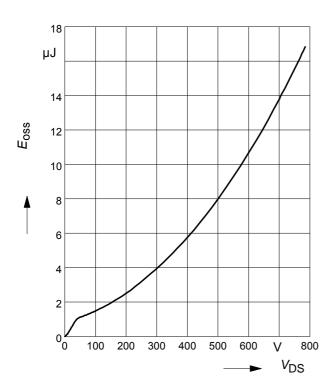
$$C = f(V_{DS})$$

parameter: V_{GS} =0V, f=1 MHz



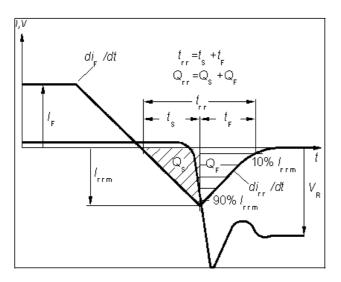
19 Typ. $C_{\rm OSS}$ stored energy

 $E_{\rm oss} = f(V_{\rm DS})$



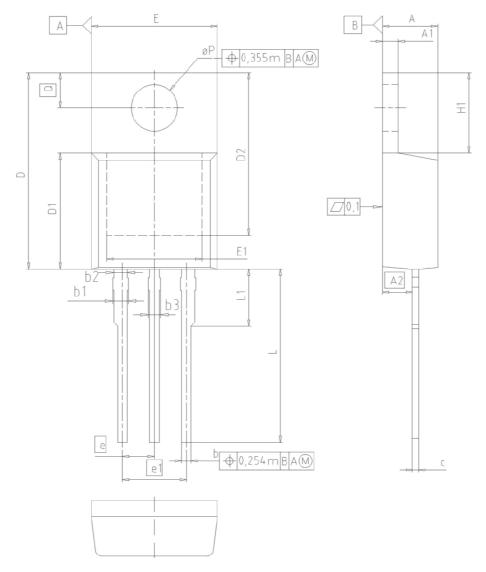


Definition of diodes switching characteristics





PG-TO220-3-1, PG-TO220-3-21

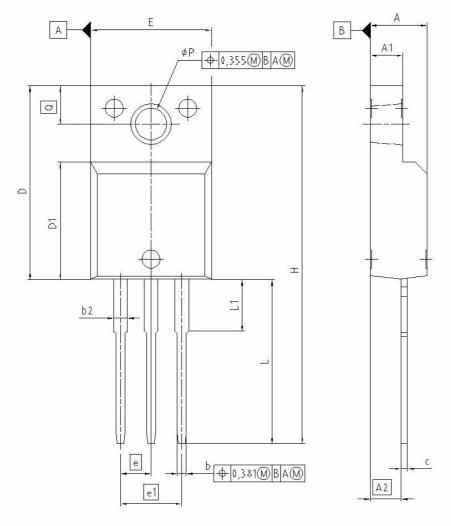


DIM	MILLI	METERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.30	4.57	0.169	0.180	
A1	1.17	1.40	0.046	0.055	
A2	2.15	2.72	0.085	0.107	
b	0.65	0.86	0.026	0.034	
b1	0.95	1.40	0.037	0.055	
b2	0.95	1.15	0.037	0.045	
b3	0.65	1.15	0.026	0.045	
С	0.33	0.60	0.013	0.024	
D	14.81	15.95	0.583	0.628	
D1	8.51	9.45	0.335	0.372	
D2	12.19	13.10	0.480	0.516	
E	9.70	10.36	0.382	0.408	
E1	6.50	8.60	0.256	0.339	
е	2	.54	0.1	00	
e1	5	.08	0.2	200	
N		3	(3	
H1	5.90	6.90	0.232	0.272	
L	13.00	14.00	0.512	0.551	
L1	-	4.80	-	0.189	
øΡ	3.60	3.89	0.142	0.153	
Q	2.60	3.00	0.102	0.118	

DOCUMEN Z8B00003	
SCALE	2.5
0 2.5	
EUROPEAN PI	ROJECTION
ISSUE D 23-08-2	
REVISI	ON



PG-TO220-3-31 (FullPAK)



D.11.7	MILLIM	ETERS	INCHES		
DIM	MIN	MAX	MIN M		
A	4.572	4.826	0.180	0.190	
A1	2.573	2.827	0.101	0.111	
A2	2.514	2.616	0.099	0.103	
b	0.649	0.776	0.025	0.030	
b2	1.143	1.509	0.045	0.059	
C	0.449	0.627	0.017	0.027	
D	15.863	16.117	0.624	0.634	
D1	9.554	9.808	0.376	0.386	
E	10.373	10.627	0.408	0.418	
е	2.5	540	0.100		
e1	5.0	080	0.2	200	
N		3		3	
Н	29.463	29.717	1.160	1.170	
L	13.473	13.727	0.530	0.540	
L1	3.175	3,429	0.125	0.135	
øP	2.949	3.025	0.119	0.116	
Q	3.149	3.251	0.124	0.128	

REFERENCE .J	
SCALE	0 -
0 2.5 Լաստակա	2.5
EUROPEAN PR	OJECTION
	\rightarrow
ISSUE D 17-08-2	
FILE	<u>.</u> D 2



Published by Infineon Technologies AG 81726 Munich, Germany © 2007 Infineon Technologies AG All Rights Reserved.

Legal Disclaimer

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

Information

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office (www.infineon.com).

Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office. Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.